IRFF9130 JANTX2N6849 JANTXV2N6849

JANS2N6849

100V, P-CHANNEL

International **ISPR** Rectifier

REPETITIVE AVALANCHE AND dv/dt RATED HEXFET[®]TRANSISTORS THRU-HOLE (TO-205AF) REF: MIL-PRF-19500/564

Product Summary

Part Number	BVDSS	RDS(on)	ld	
IRFF9130	-100V	0.30Ω	-6.5A	

The HEXFET[®]technology is the key to International Rectifier's advanced line of power MOSFET transistors. The efficient geometry and unique processing of this latest "State of the Art" design achieves: very low on-state resistance combined with high transconductance.

The HEXFET transistors also feature all of the well established advantages of MOSFETs such as voltage control, very fast switching, ease of parelleling and temperature stability of the electrical parameters.

They are well suited for applications such as switching power supplies, motor controls, inverters, choppers, audio amplifiers and high energy pulse circuits.



Features:

- **Repetitive Avalanche Ratings**
- Dynamic dv/dt Rating
- Hermetically Sealed
- Simple Drive Requirements
- Ease of Paralleling

	Parameter		Units
ID @ VGS = -10V, TC = 25°C Continuous Drain Current		-6.5	
ID @ VGS = -10V, TC = 100°C Continuous Drain Current		-4.1	A
IDM	Pulsed Drain Current 1	-25	
P _D @ T _C = 25°C	Max. Power Dissipation	25	W
	Linear Derating Factor	0.20	W/°C
VGS	Gate-to-Source Voltage	±20	V
EAS	Single Pulse Avalanche Energy 2	92	mJ
IAR	Avalanche Current ①	-	А
EAR	Repetitive Avalanche Energy ①	—	mJ
dv/dt	Peak Diode Recovery dv/dt 3	-5.5	V/ns
TJ	Operating Junction	-55 to 150	
TSTG Storage Temperature Range			°C
	Lead Temperature	300 (0.063 in. (1.6mm) from case for 10s)	
	Weight	0.98(typical)	g

Absolute Maximum Ratings

For footnotes refer to the last page

IRFF9130

	Parameter	Min	Тур	Max	Units	Test Conditions
BVDSS	Drain-to-Source Breakdown Voltage	-100	_	—	V	VGS = 0V, ID = -1.0mA
∆BV _{DSS} /∆TJ	Temperature Coefficient of Breakdown Voltage	_	-0.10	—	V/°C	Reference to 25°C, ID = -1.0mA
RDS(on)	Static Drain-to-Source On-State	—	—	0.30	Ω	VGS = -10V, ID = -4.1A ④
	Resistance	—	—	0.345	52	VGS =-10V, ID =-6.5A ④
VGS(th)	Gate Threshold Voltage	-2.0	—	-4.0	V	$V_{DS} = V_{GS}$, $I_{D} = -250 \mu A$
9fs	Forward Transconductance	2.5	—	—	S (73)	V _{DS} > -15V, I _{DS} = -4.1A ④
IDSS	Zero Gate Voltage Drain Current	—	—	-25		V _{DS} = -80V, V _{GS} =0V
		_	—	-250	μA	V _{DS} = -80V
						$V_{GS} = 0V, T_{J} = 125^{\circ}C$
IGSS	Gate-to-Source Leakage Forward	_	—	-100		V _{GS} = -20V
IGSS	Gate-to-Source Leakage Reverse	—	—	100	nA	$V_{GS} = 20V$
Qg	Total Gate Charge	14.7	—	34.8		VGS =-10V, ID = -6.5A
Qgs	Gate-to-Source Charge	1.0	_	7.1	nC	V _{DS} =-50V
Qgd	Gate-to-Drain ('Miller') Charge	2.0	—	21		
^t d(on)	Turn-On Delay Time	—	—	60		V _{DD} = -50V, I _D = -6.5A,
tr	Rise Time	—	—	140		VGS =-10V,RG =7.5Ω
^t d(off)	Turn-Off Delay Time	—	—	140	ns	
tf	Fall Time		—	140		
L _{S +} L _D	Total Inductance	_	7.0	_	nH	Measured from drain lead (6mm/0.25in. from package) to source lead (6mm/0.25in. from package)
C _{iss}	Input Capacitance	_	800			$V_{GS} = 0V, V_{DS} = -25V$
Coss	Output Capacitance	—	350	—	pF	f = 1.0MHz
C _{ISS}	Reverse Transfer Capacitance	—	125	—		

Source-Drain Diode Ratings and Characteristics

	Parameter		Min	Тур	Max	Units	Test Conditions
IS	Continuous Source Current (B	ody Diode)	_	—	-6.5	Α	
ISM	Pulse Source Current (Body D	iode) 1	_	—	-25		
VSD	Diode Forward Voltage		_	—	-4.7	V	Tj = 25°C, IS =-6.5A, VGS = 0V ④
trr	Reverse Recovery Time		_	—	250	nS	Tj = 25°C, IF = -6.5A, di/dt ≤ -100A/μs
QRR	Reverse Recovery Charge		—	—	3.0	μC	V _{DD} ≤ -50V ④
ton	Forward Turn-On Time	Intrinsic turn-on time is negligible. Turn-on speed is substantially controlled by LS + LD.					

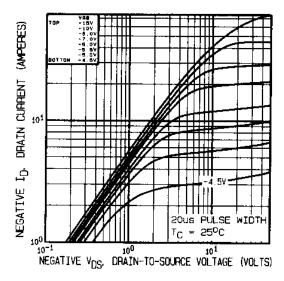
Thermal Resistance

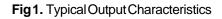
	Parameter	Min	Тур	Max	Units	Test Conditions
R _{thJC}	Junction-to-Case	—	_	5.0		
R _{th} JA	Junction-to-Ambient	—	—	175	°C/W	Typical socket mount

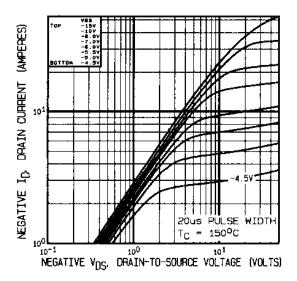
Note: Corresponding Spice and Saber models are available on the G&S Website.

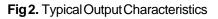
For footnotes refer to the last page

International **tor** Rectifier









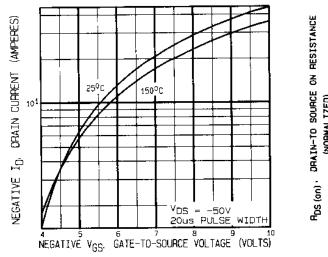
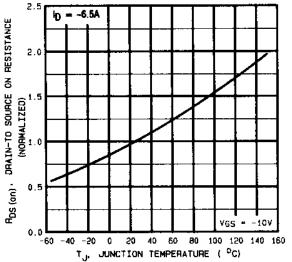
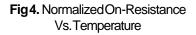
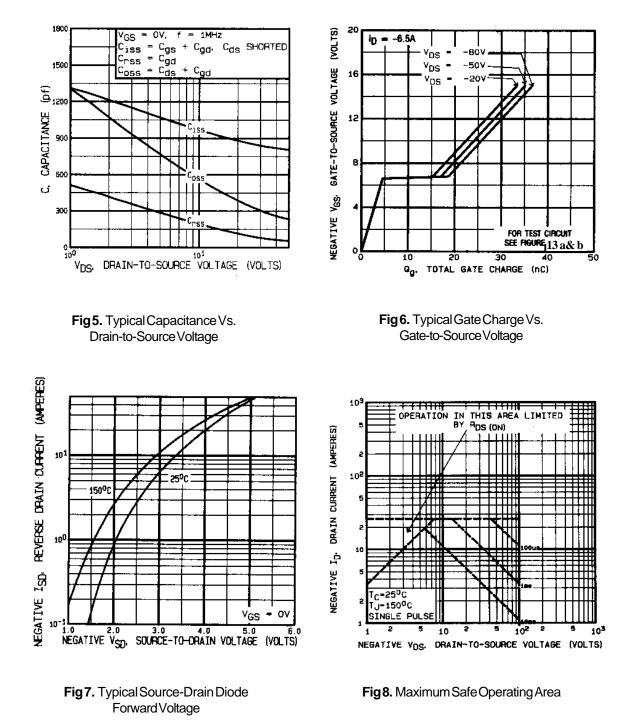


Fig 3. Typical Transfer Characteristics

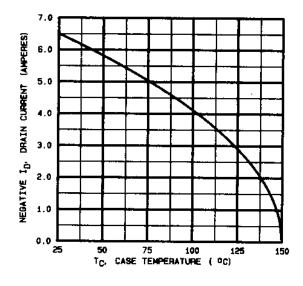






IRFF9130

International





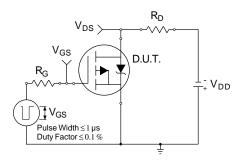


Fig10a. Switching Time Test Circuit

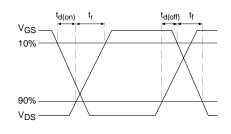


Fig10b. Switching Time Waveforms

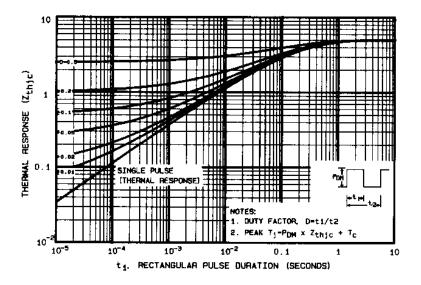


Fig11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

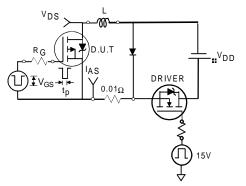


Fig12a. Unclamped Inductive Test Circuit

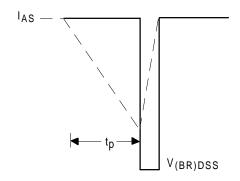


Fig 12b. Unclamped Inductive Waveforms

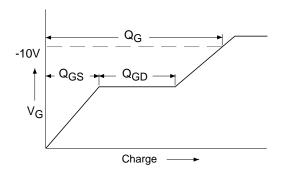


Fig 13a. Basic Gate Charge Waveform

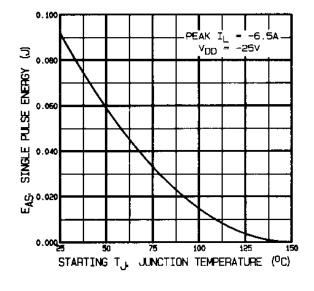


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

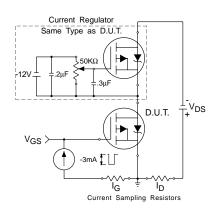


Fig13b. Gate Charge Test Circuit

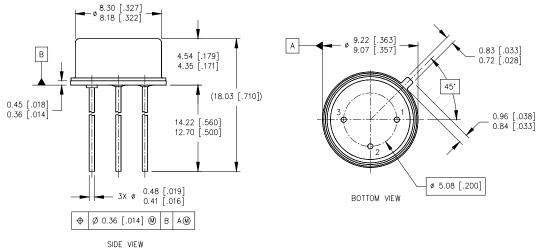
International

Foot Notes:

- Repetitive Rating; Pulse width limited by maximum junction temperature.
- ② V_{DD} = -25V, starting T_J = 25°C, Peak I_I = -6.5A, V_{GS} = -10V

- $I_{SD} \leq$ -6.5A, di/dt \leq -140A/µs, $V_{DD} \leq$ -100V, TJ \leq 150°C Suggested RG = 7.5 Ω
- ④ Pulse width \leq 300 μ s; Duty Cycle \leq 2%

Case Outline and Dimensions —TO-205AF



LEGEND

1- SOURCE

2- GATE

3- DRAIN

- NOTES:
- 1. DIMENSIONING AND TOLERANCING PER ASME 14.5M-1994.
- 2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].
- 3. CONTROLLING DIMENSION: INCH.
- 4. CONFORMS TO JEDEC OUTLINE TO-205AF (TO-39).

International

IR WORLD HEADQUARTERS: 233 Kansas St., El Segundo, California 90245, USA Tel: (310) 252-7105 TAC Fax: (310) 252-7903 Visit us at www.irf.com for sales contact information. Data and specifications subject to change without notice. 04/01